CYPRESS SEMICONDUCTOR

6-ns BiCMOS PAL® with Input Registers

Features

- **Very high performance decoder**
  - **t_{ICO} = 6 ns**
  - **f_{MAXD} = 156 MHz**
- **12 input registers**
- **8 outputs**
- **2 product terms per output**
- **Asynchronous output enable**
- **Power-on reset**
- **High noise immunity**
- **>2001V input protection from electrostatic discharge**
- **Advanced BiCMOS technology**
- **Available in 28-pin 300-mil PDIP and CerDIP, and in SOJ, PLCC, and LCC packages**

Functional Description

The CY7B336 is a 6-ns, 28-pin programmable logic device specially designed for decoding applications with high-performance RISC processors and fast state machines.

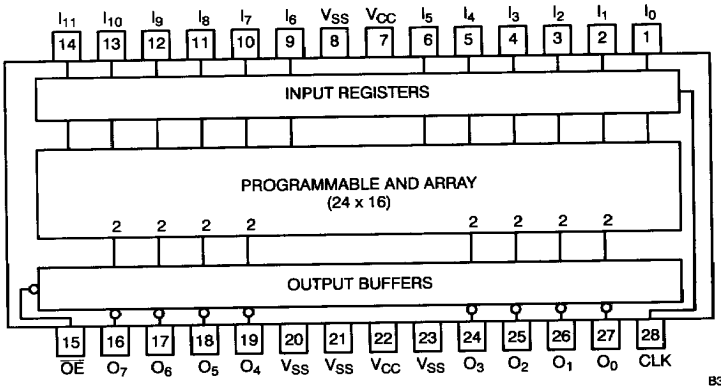
There are twelve input registers that capture data at the rising edge of the clock signal and forward the information to the 24 by 16 programmable array. Processed data from the programmable array is available to external logic via the eight output pins.

Each output provides two product terms. However, only one product term is used to sum products from the array; the other product term is used to control the tri-state output buffers. This output enable product term is ANDed with the complement of the output enable input pin to generate the output enable signal for each output buffer.

Additional features of the CY7B336 include a power-on reset circuit that initializes all input registers to a "0" upon power-up, and six centrally located power pins (V_{CC} pins and four ground pins), which improve noise margins.

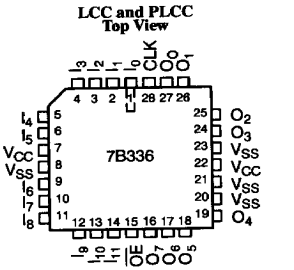
The CY7B336 is available in a wide variety of package types including 28-pin, 300-mil plastic and ceramic DIPs, SOJs, LCCs, and PLCCs.

Logic Block Diagram and DIP/SOJ Pinout



B336-1

Pin Configuration



B336-2

Selection Guide

Generic Part Number	t_{ICO} (ns)		f_{MAXD} (MHz)		I_{CC} (mA)		t_{IS} (ns)	
	Com'l	Mil	Com'l	Mil	Com'l	Mil	Com'l	Mil
7B336-6	6		156		180		2	
7B336-7		7		131		180		2.5
7B336-8	8		113		180		3	
7B336-10		10		96		180		3
7B336-12		12		80		180		3.5

PAL is a registered trademark of Monolithic Memories Inc.

Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... − 65°C to +150°C

Ambient Temperature with Power Applied ..... − 55°C to +125°C

Supply Voltage to Ground Potential (Pins 7 and 22 to Pins 8, 20, 21, and 23) ..... − 0.5V to +7.0V

DC Voltage Applied to Outputs in High Z State ..... − 0.5V to +V_{CC} Max.

DC Input Voltage ..... − 0.5V to +V_{CC} +0.5V

Output Current into Outputs (LOW) ..... 12 mA

DC Input Current ..... − 30 mA to +5 mA (Except during programming)

DC Programming Voltage 9.5V

Static Discharge Voltage ..... > 2001V (per MIL-STD-883 Method 3015)

Latch-Up Current ..... > 200 mA

Operating Range

Range	Ambient Temperature	V_{CC}
Commercial	0°C to + 70°C	5V ± 10%
Military[1]	− 55°C to + 125°C	5V ± 10%

Electrical Characteristics Over the Operating Range

Parameters	Description	Test Conditions			7B336 Min.	7B336 Max.	Units
V_{OH}	Output HIGH Voltage	V_{CC} = Min., V_{IN} = V_{IH} or V_{IL}	I_{OH} = − 4 mA	Com'l	2.4		V
			I_{OH} = − 3 mA	Mil	2.4		
V_{OL}	Output LOW Voltage	V_{CC} = Min., V_{IN} = V_{IH} or V_{IL}	I_{OL} = 12 mA	Com'l		0.4	V
			I_{OL} = 8 mA	Mil		0.4	
V_{IH}	Input HIGH Level	Guaranteed Input Logical HIGH Voltage for All Inputs			2.2		V
V_{IL}	Input LOW Level	Guaranteed Input Logical LOW Voltage for All Inputs				0.8	V
I_{IX}	Input Leakage Current	V_{CC} = Max., 0.4V ≤ V_{IN} ≤ 2.7V			− 250	25	μA
I_{OZ}	Output Leakage Current	V_{CC} = Max., 0.4V ≤ V_{OUT} ≤ 2.7V			− 100	100	μA
I_{SC}	Output Short Circuit Current	V_{CC} = Max., V_{OUT} = 0.5V[2]			− 30	− 130	mA
I_{CC}	Power Supply Current	V_{CC} = Max., Outputs Disabled (in High Z State), Device Operating at f_{MAX}		Com'l		180	mA
				Mil		180	

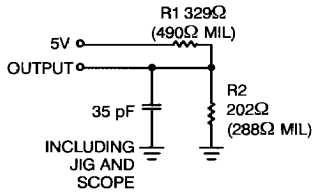
Capacitance[3]

Parameters	Description	Typ.	Max.	Units
C_{IN}	Input Capacitance	11	10	pF
C_{OUT}	Output Capacitance	9	10	pF

Notes:

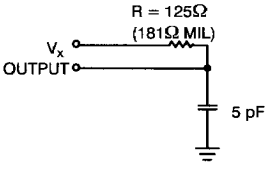
1. T_A is the "instant on" case temperature.
2. Not more than one output should be tested at a time. Duration of the short circuit should not be more than one second. V_{OUT} = 0.5V has been chosen to avoid test problems caused by tester ground degradation.
3. Tested initially and after any design or process changes that may affect these parameters.
4. The normal test load is used for all parameters except for t_{CER}, t_{CEA}, t_{PXZ}, and t_{PZX}, which are tested using the three-state load.

AC Test Loads and Waveforms[4]



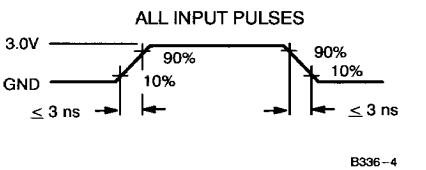
(a) Normal Load

B336-3



(b) Three-State Load

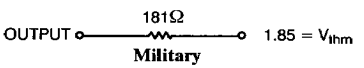
B336-5



B336-4

Equivalent to: THÉVENIN EQUIVALENTS

Commercial



Military

AC Test Loads and Waveforms (continued)

Parameter	V_X	Output Waveform—Measurement Level
$t_{CER}(-)$ $t_{PXZ}(-)$	1.5V	V_{OH} 0.5V V_X
$t_{CER}(+)$ $t_{PXZ}(+)$	2.6V	V_{OL} 0.5V V_X
$t_{CEA}(+)$ $t_{PZX}(+)$	V_{thc}	V_X 0.5V V_{OH}
$t_{CEA}(-)$ $t_{PZX}(-)$	V_{thc}	V_X 0.5V V_{OL}

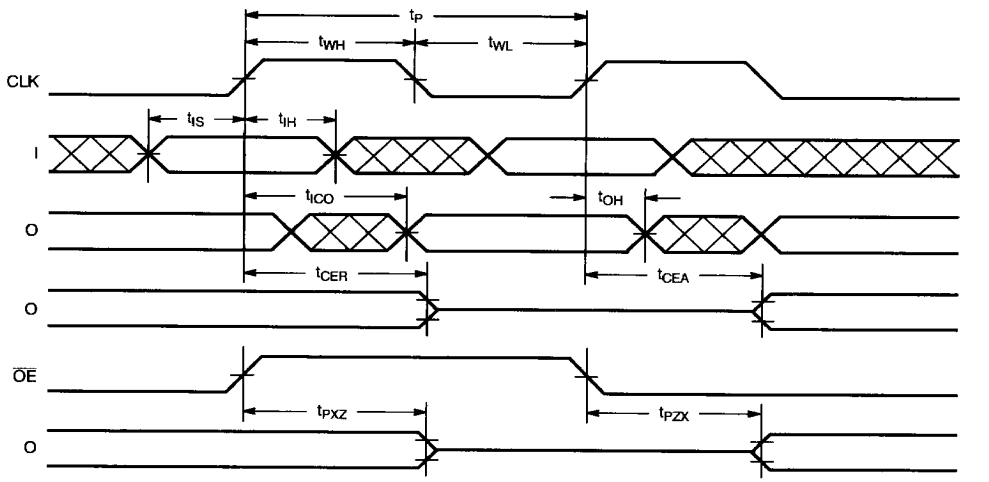
Switching Characteristics Over the Operating Range[5]

Parameters	Description	Commercial				Military						Units
		6		8		7		10		12		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{ICO}	Input Register Clock to Output Delay		6		8		7		10		12	ns
t_P	Clock Period ($t_{WH}+t_{WL}$)[3]	6.4		8.8		7.6		10.4		12.4		ns
f_{MAXD}	Maximum Frequency Data Path ($1/t_P$)[3]		156		113		131		96		80	MHz
t_{WH}	Clock Width HIGH[3]	3.2		4.4		3.8		5.2		6.2		ns
t_{WL}	Clock Width LOW[3]	3.2		4.4		3.8		5.2		6.2		ns
t_{OH}	Output Hold After Clock High	0		0		0		0		0		ns
t_{IS}	Input Set-Up Time	2		3		2.5		3		3.5		ns
t_{IH}	Input Hold Time	2		3		2.5		3		3.5		ns
t_{CER}	Input Register Clock to Output Disable Delay[6]		9		13		11		14		17	ns
t_{CEA}	Input Register Clock to Output Enable Delay		9		13		11		14		17	ns
t_{PXZ}	Pin 15 to Output Disable Delay[6]		7		10		8.5		11.5		14.5	ns
t_{PZX}	Pin 15 to Output Enable Delay		7		10		8.5		11.5		14.5	ns
t_{PR}	Power-Up Reset Time[7]		1		1		1		1		1	µs

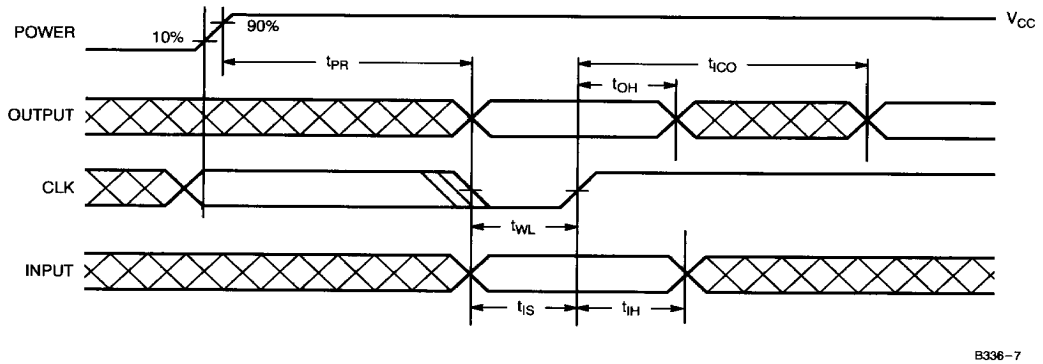
Notes:

5. AC test load is used for all parameters except where noted.
6. This parameter is measured as the time that the previous output data state remains stable after the output disable signal is received. This delay is measured to the point at which a previous HIGH level has fallen to 0.5 volts below V_{OH} Min. or a previous LOW level has risen to 0.5 volts above V_{OL} Max.
7. This part has been designed with the capability to reset during system power-up. Following power-up, the input registers will be reset to a logic LOW state. The output state will depend on how the array is programmed. To insure proper operation, the rise in V_{CC} must be monotonic and the timing constraints depicted in power-up reset waveforms must be satisfied. The clock signal input must be in a valid LOW state (V_{IN} less than 0.8V) or a valid HIGH state (V_{IN} greater than 2.2V) prior to occurrence of the 10% level on the monotonically rising power supply voltage. In addition, the clock input signal must remain stable in that valid state as indicated until the 90% level on the power supply voltage has been reached. The clock signal may transition LOW to HIGH to clock in new data or to execute a synchronous preset after the indicated delay (t_{PR} + t_{IS}) has been observed.

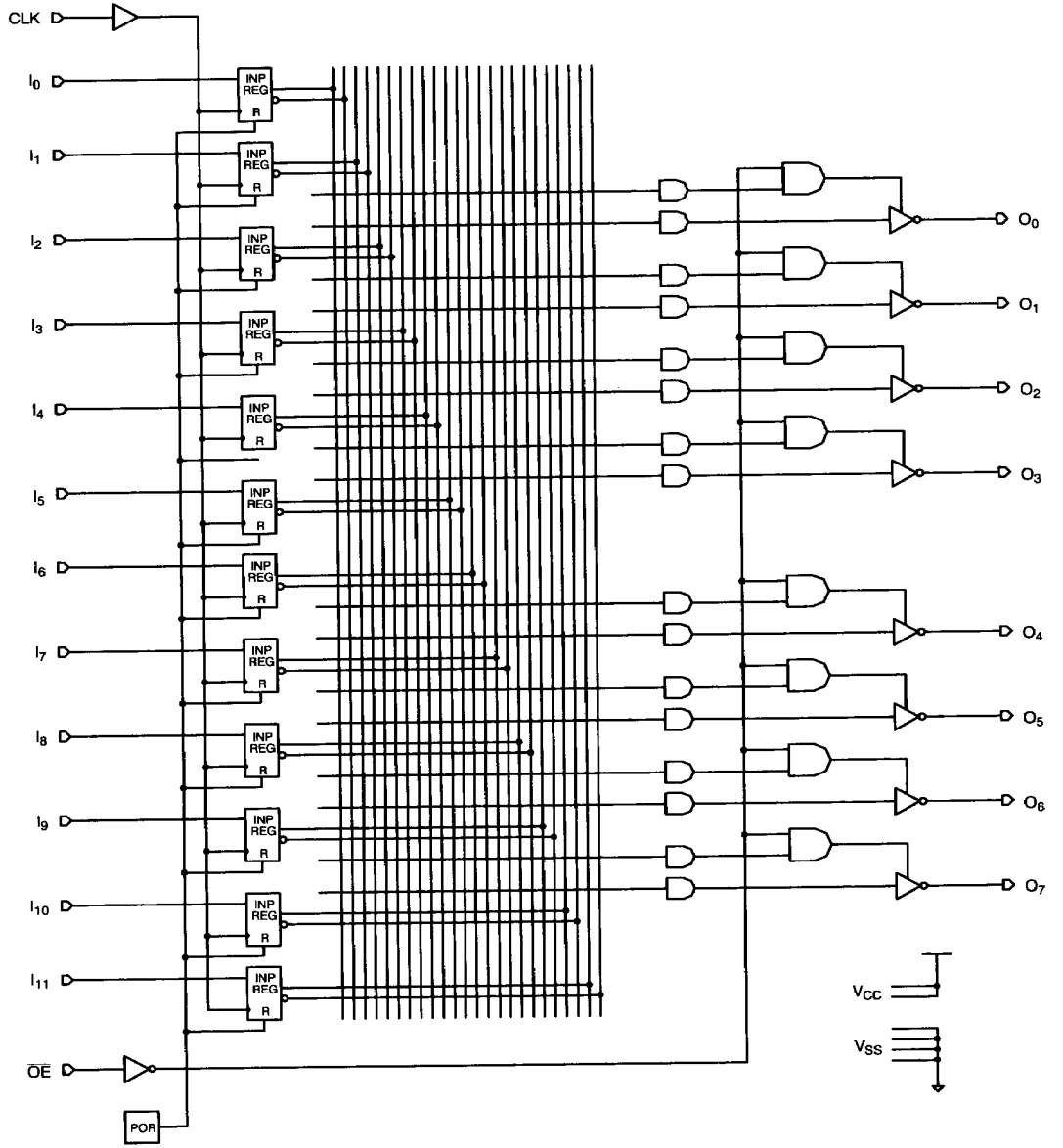
Switching Waveform



Power-Up Reset Waveform[7]



CY7B336 Logic Diagram



Ordering Information

t_{ICO} (ns)	f_{MAXD} (MHz)	Ordering Code	Package Type	Operating Range
6	156	CY7B336–6PC	P21	Commercial
		CY7B336–6DC	D22	
		CY7B336–6JC	J64	
		CY7B336–6VC	V21	
7	131	CY7B336–7DMB	D22	Military
		CY7B336–7LMB	L64	
8	113	CY7B336–8PC	P21	Commercial
		CY7B336–8DC	D22	
		CY7B336–8JC	J64	
		CY7B336–8VC	V21	
10	96	CY7B336–10DMB	D22	Military
		CY7B336–10LMB	L64	
12	80	CY7B336–12DMB	D22	Military
		CY7B336–12LMB	L64	

MILITARY SPECIFICATIONS
Group A Subgroup Testing

DC Characteristics

Parameters	Subgroups
V_{OH}	1, 2, 3
V_{OL}	1, 2, 3
V_{IH}	1, 2, 3
V_{IL}	1, 2, 3
I_{IX}	1, 2, 3
I_{OZ}	1, 2, 3

Switching Characteristics

Parameters	Subgroups
t_{ICO}	7, 8, 9, 10, 11
t_{IS}	7, 8, 9, 10, 11
t_{IH}	7, 8, 9, 10, 11
t_{CXZ}	7, 8, 9, 10, 11
t_{CZX}	7, 8, 9, 10, 11
t_{PXZ}	7, 8, 9, 10, 11
t_{PZX}	7, 8, 9, 10, 11

Document #: 38–00134–B